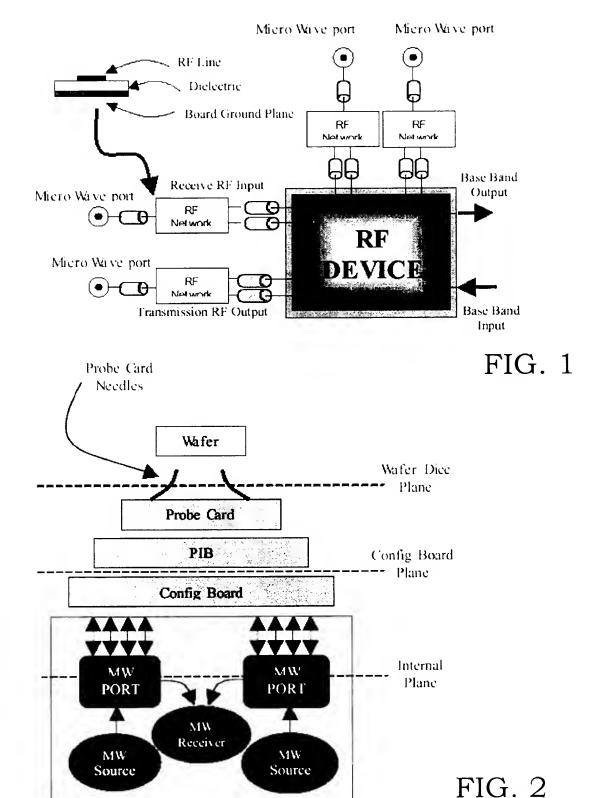
Title: TEST BOARD E-EMBEDDING METHOD TO IMPROOF RF MEASUREMENTS ACCURACY (N. AUTOMATIC TESTING EQUIPM FOR IC WAFERS



Title: TEST BOARD & E-EMBEDDING METHOD TO IMPRO ACCURACY (NAUTOMATIC TESTING EQUIPM FOR IC WAFERS

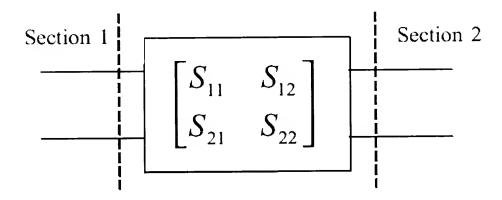


FIG. 3

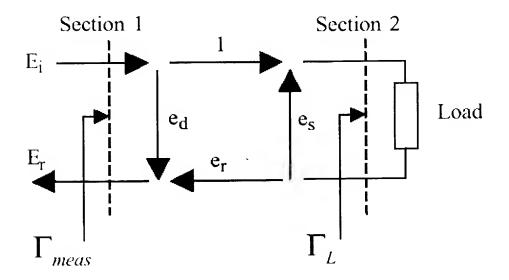


FIG. 4

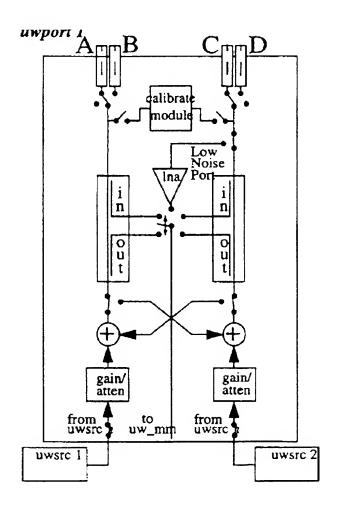


FIG. 5

Title: TEST BOARD SE-EMBEDDING METHOD TO IMPROSE RF MEASUREMENTS ACCURACY (IN AUTOMATIC TESTING EQUIPM FOR IC WAFERS

File View - Sample freq: 16.38 Y-axis - Zoom - Exp DATA: -0.3535 to 0.	-	DISPLAY0.3535	to 0.3545	
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FIG. 6

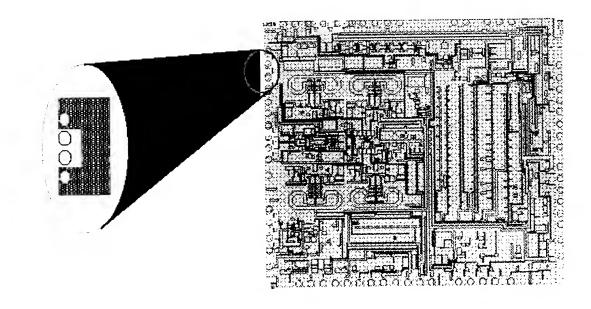


FIG. 7

Title: TEST BOARD SE-EMBEDDING METHOD TO IMPROSES RF MEASUREMENTS ACCURACY CON AUTOMATIC TESTING EQUIPMENTS FOR IC WAFERS

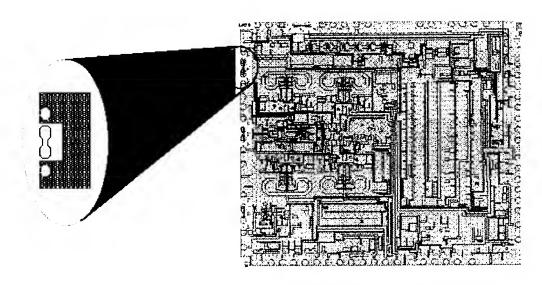


FIG. 8

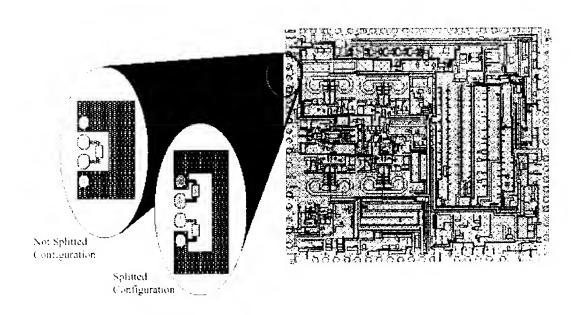
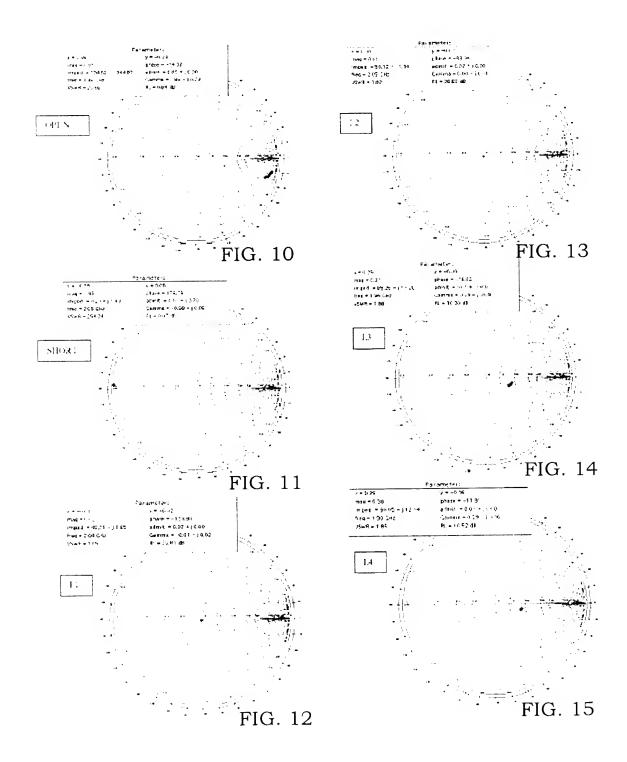


FIG. 9

Title: TEST BOARD SE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY (N AUTOMATIC TESTING EQUIPM) FOR IC WAFERS



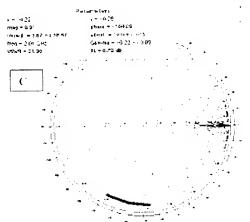


FIG. 16

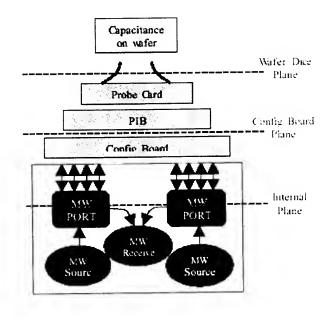


FIG. 17

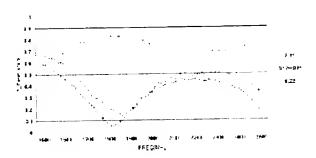


FIG. 18

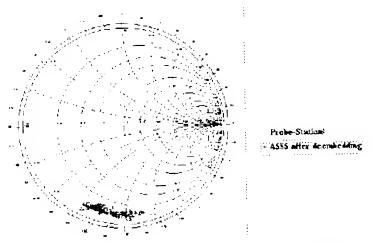


FIG. 19

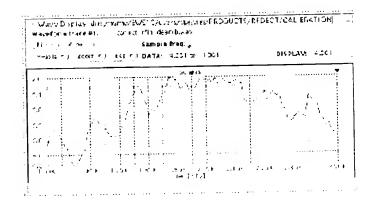


FIG. 20

Title: TEST BOARD RE-EMBEDDING METHOD TO IMPROVE RF MEASUREMENTS ACCURACY CON AUTOMATIC TESTING EQUIPM. FOR IC WAFERS

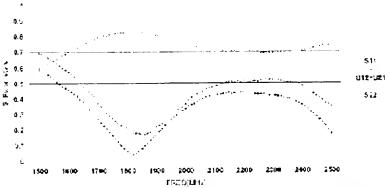
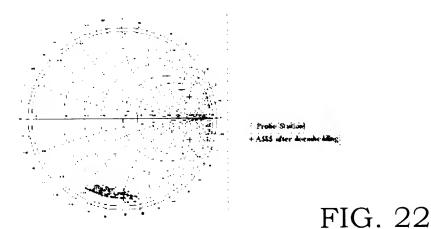
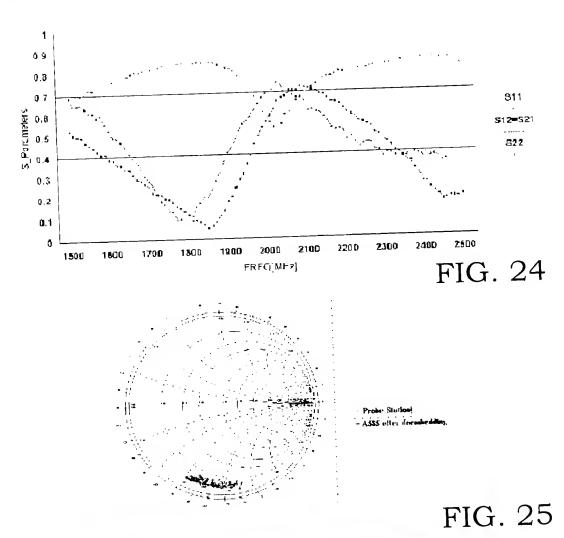


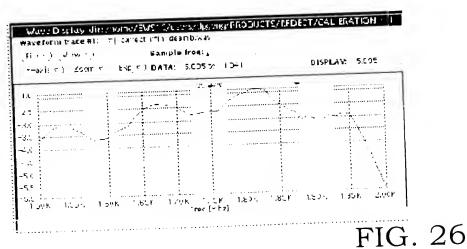
FIG. 21



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FIG. 23





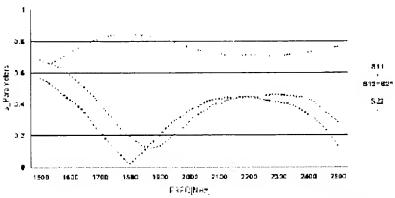


FIG. 27

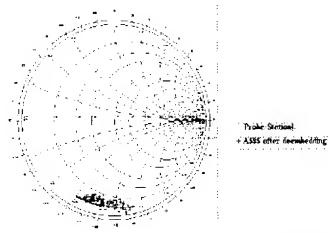


FIG. 28

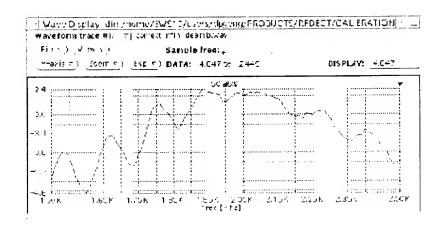


FIG. 29